

C1808X562KFRACTU

Aliases (C1808X562KFRAC7800)

SMD Comm X7R HV Flex, Ceramic, 5,600 pF, 10%, 1,500 VDC, X7R, SMD, MLCC, FT-CAP, Temperature Stable, 1808, 2.9 mm



General Information	
Series	SMD Comm X7R HV Flex
Style	SMD Chip
Description	SMD, MLCC, FT-CAP, Temperature Stable
Features	FT-CAP, Temperature Stable
RoHS	Yes
Termination	Flexible Termination
Marking	No
AEC-Q200	No
Typical Component Weight	100 mg
Shelf Life	78 Weeks
MSL	1

Dimensions	
Chip Size	1808
L	4.7mm +/-0.5mm
W	2mm +/-0.2mm
Т	2mm +/-0.15mm
S	2.9mm MIN
В	0.7mm +/-0.35mm

L	4.7mm +/-0.5mm	Measurement Condition	1 kHz 1.0Vrms
W	2mm +/-0.2mm	Tolerance	10%
T	2mm +/-0.15mm	Voltage DC	1500 VDC
S	2.9mm MIN	Dielectric Withstanding Voltage	1,800 VDC
В	0.7mm +/-0.35mm	Temperature Range	-55/+125°C
		Temp. Coefficient	X7R
Packaging Specifications		Capacitance Change with	15%, 1kHz 1.0Vrms
Packaging	T&R, 180mm, Plastic Tape	Reference to +25°C and 0 VDC Applied (TCC)	
Packaging Quantity	1000	Dissipation Factor	2 5% 1kHz 10Vrms

Specifications

Capacitance	5,600 pF
Measurement Condition	1 kHz 1.0Vrms
Tolerance	10%
Voltage DC	1500 VDC
Dielectric Withstanding Voltage	1,800 VDC
Temperature Range	-55/+125°C
Temp. Coefficient	X7R
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	15%, 1kHz 1.0Vrms
Dissipation Factor	2.5%1kHz1.0Vrms
Aging Rate	3% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	100 GOhms

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